



ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

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Title of
Invention

SYSTEMS FOR SIMULATING HIGH NA AND
POLARIZATION EFFECTS IN AERIAL IMAGES

Application Number: 10/736409



Confirmation Number: 3959

First Named Applicant: Don Pettibone

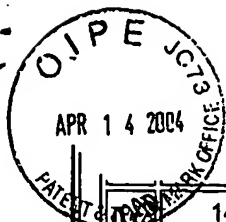
Attorney Docket Number: 5589-04801

Search string: (6614520 or 4926489 or 4247203 or 5189481
or 4347001 or 5563702 or 4378159 or 5572598
or 4448532 or 5737072 or 4532650 or 5889593
or 4555798 or 6052478 or 4579455 or 6076465
or 4633504 or 6122046 or 4641967 or 6137570
or 4758094 or 6141038 or 4766324 or 6175645
or 4805123 or 6282309 or 4845558 or 6363166
or 4877326 or 6636301 or 6392800 or 5365371
or 5680588 or 6268093 or 5559583 or 4899055
or 6404482).pn.

US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
ms	1	6614520	2003-09-02	Bareket et al.			
ms	2	4926489	1990-05-15	Danielson et al.			
ms	3	4247203	1981-01-27	Levy et al.			
ms	4	5189481	1993-02-23	Jann et al.			
ms	5	4347001	1982-08-31	Levy et al.			
ms	6	5563702	1996-10-08	Emery et al.			
ms	7	4378159	1983-03-29	Galbraith			
ms	8	5572598	1996-11-05	Wihl et al.			
ms	9	4448532	1984-05-15	Joseph et al.			
ms	10	5737072	1998-04-07	Emery et al.			
ms	11	4532650	1985-07-30	Wihl et al.			
ms	12	5889593	1999-03-30	Bareket			
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14	6052478	2000-04-18	Wihl et al.
15	4579455	1986-04-01	Levy et al.
16	6076465	2000-06-20	Vacca et al.
17	4633504	1986-12-30	Wihl
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21	4758094	1988-07-19	Wihl et al.
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25	4805123	1989-02-14	Specht et al.
26	6282309	2001-08-28	Emery
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34	6268093	2001-07-31	Kenan et al.
35	5559583	1996-09-24	Tanabe
36	4899055	1990-02-06	Adams
37	6404482	2002-06-11	Shiraishi

Signature

Examiner Name	Date
<i>maissa j. detsch</i>	1-5-06

FILING DATE: December 15, 2003

GROUP: Unknown

U.S. PATENT DOCUMENTS

[illegible]

FOREIGN PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO
mgd	A1	1 061 358	12/20/2000	EP		_____	
mgd	A2	1 061 571	12/20/2000	EP		_____	
mgd	A3	1 069 609	1/17/2001	EP		_____	
mgd	A4	99/38002	7/29/1999	WO		_____	
mgd	A5	99/59200	11/18/1999	WO		_____	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

mjb	A6	Pistor, "Electromagnetic Simulation and Modeling with Applications in Lithography," 2001, p. 56.
mjb	A7	Smith et al., "Challenges in high NA, polarization, and photoresists," Proceedings of SPIE Vol. 4691, 2002, pp. 11-24.

EXAMINER:

DATE CONSIDERED:

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the patent owner.